Special Issue

Intelligent Diagnostic and Prognostic Methods for Electronic Systems and Mechanical Systems

Message from the Guest Editors

The scale of modern electronic systems or mechanical systems is becoming more complex, but the testable parameters are becoming less so, which makes it difficult to locate the fault, and thus, the diagnosis cost is high. This Special Issue calls for papers on the fault diagnosis and prediction technology of complex electronic and mechanical systems such as analog circuits, lithium batteries, and gears, including but not limited to fault feature extraction, diagnostic reasoning methods, performance degradation, life prediction, etc.

- fault diagnosis
- diagnostics
- diagnostic reasoning
- fault feature extraction
- prognostics
- performance degradation
- life prediction
- residual useful life (RUL)
- analog circuits
- lithium-ion battery
- gears system
- data-driven methods
- model-based methods
- machine learning
- neural network

Guest Editors

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Deadline for manuscript submissions

closed (25 July 2022)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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